

<b>Notice of References Cited</b>	Application/Control No. 10/002,316	Applicant(s)/Patent Under Reexamination TRYON, ROBERT G.	
	Examiner Fred Ferris	Art Unit 2128	Page 1 of 2

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,226,597 B1	05-2001	Eastman et al.	702/34
	C	US-5,764,068	06-1998	Katz et al.	324/727
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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	Examiner Fred Ferris	Art Unit 2128	Page 2 of 2

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